#### Intel - EP1C4F400I7N Datasheet





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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	400
Number of Logic Elements/Cells	4000
Total RAM Bits	78336
Number of I/O	301
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	400-BGA
Supplier Device Package	400-FBGA (21x21)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1c4f400i7n

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to the appropriate plane on the board. The Quartus II software reserves I/O pins as power pins as necessary for layout with the larger densities in the same package having more power pins.

Table 1–3. Cyclone QFP and FineLine BGA Package Sizes										
Dimension 100-Pin TQFP 144-Pin TQFP 240-Pin PQFP 256-Pin FineLine BGA BGA BGA										
Pitch (mm)	0.5	0.5	0.5	1.0	1.0	1.0				
Area (mm <sup>2</sup> )	256	484	1,024	289	361	441				
$\begin{array}{l} \text{Length} \times \text{ width} \\ (\text{mm} \times \text{ mm}) \end{array}$	16×16	22×22	34.6×34.6	17×17	19×19	21×21				

## Document Revision History

Table 1–4 shows the revision history for this document.

Table 1–4. Document Revision History								
Date and Document Version	Changes Made	Summary of Changes						
May 2008 v1.5	Minor textual and style changes.	_						
January 2007 v1.4	Added document revision history.	_						
August 2005 v1.3	Minor updates.	_						
October 2003 v1.2	Added 64-bit PCI support information.	_						
September 2003 v1.1	<ul> <li>Updated LVDS data rates to 640 Mbps from 311 Mbps.</li> <li>Updated RSDS feature information.</li> </ul>	_						
May 2003 v1.0	Added document to Cyclone Device Handbook.	_						

## **Logic Array** Blocks

Each LAB consists of 10 LEs, LE carry chains, LAB control signals, a local interconnect, look-up table (LUT) chain, and register chain connection lines. The local interconnect transfers signals between LEs in the same LAB. LUT chain connections transfer the output of one LE's LUT to the adjacent LE for fast sequential LUT connections within the same LAB. Register chain connections transfer the output of one LE's register to the adjacent LE's register within a LAB. The Quartus® II Compiler places associated logic within a LAB or adjacent LABs, allowing the use of local, LUT chain, and register chain connections for performance and area efficiency. Figure 2-2 details the Cyclone LAB.



#### Figure 2–2. Cyclone LAB Structure

#### LAB Interconnects

The LAB local interconnect can drive LEs within the same LAB. The LAB local interconnect is driven by column and row interconnects and LE outputs within the same LAB. Neighboring LABs, PLLs, and M4K RAM blocks from the left and right can also drive a LAB's local interconnect through the direct link connection. The direct link connection feature minimizes the use of row and column interconnects, providing higher

Figure 2–8 shows the carry-select circuitry in a LAB for a 10-bit full adder. One portion of the LUT generates the sum of two bits using the input signals and the appropriate carry-in bit; the sum is routed to the output of the LE. The register can be bypassed for simple adders or used for accumulator functions. Another portion of the LUT generates carry-out bits. A LAB-wide carry-in bit selects which chain is used for the addition of given inputs. The carry-in signal for each chain, carry-in0 or carry-in1, selects the carry-out to carry forward to the carry-in signal of the next-higher-order bit. The final carry-out signal is routed to an LE, where it is fed to local, row, or column interconnects.





Figure 2–10. LUT Chain and Register Chain Interconnects

The C4 interconnects span four LABs or M4K blocks up or down from a source LAB. Every LAB has its own set of C4 interconnects to drive either up or down. Figure 2–11 shows the C4 interconnect connections from a LAB in a column. The C4 interconnects can drive and be driven by all types of architecture blocks, including PLLs, M4K memory blocks, and column and row IOEs. For LAB interconnection, a primary LAB or its LAB neighbor can drive a given C4 interconnect. C4 interconnects can drive each other to extend their range as well as drive row interconnects for column-to-column connections.

All embedded blocks communicate with the logic array similar to LAB-to-LAB interfaces. Each block (i.e., M4K memory or PLL) connects to row and column interconnects and has local interconnect regions driven by row and column interconnects. These blocks also have direct link interconnects for fast connections to and from a neighboring LAB.

Table 2–2 shows the Cyclone device's routing scheme.

Table 2–2. Cyclone Device Routing Scheme											
	Destination										
Source	LUT Chain	Register Chain	Local Interconnect	Direct Link Interconnect	R4 Interconnect	C4 Interconnect	IE	M4K RAM Block	TTd	Column 10E	Row IDE
LUT Chain	—	—	—	—	_	—	$\checkmark$	—	—	—	—
Register Chain	_	_	_	_	_	_	~	_	_	_	_
Local Interconnect				_		_	$\checkmark$	$\checkmark$	$\checkmark$	$\checkmark$	~
Direct Link Interconnect	_	_	~	_	_	_	_	_	_	_	_
R4 Interconnect	_	_	~	_	~	~	_	_	_	_	_
C4 Interconnect	_	_	$\checkmark$		$\checkmark$	$\checkmark$		_	_	_	_
LE	$\checkmark$	$\checkmark$	$\checkmark$	$\checkmark$	$\checkmark$	$\checkmark$			_	_	
M4K RAM Block			$\checkmark$	$\checkmark$	$\checkmark$	$\checkmark$					_
PLL	_	_	_	$\checkmark$	$\checkmark$	$\checkmark$	_	_	—	_	—
Column IOE	_	_	_	_	_	$\checkmark$	_	_	—	_	_
Row IOE	_	_	—	$\checkmark$	$\checkmark$	$\checkmark$	_	—	—	—	_

register outputs (number of taps  $n \times \text{width } w$ ) must be less than the maximum data width of the M4K RAM block (×36). To create larger shift registers, multiple memory blocks are cascaded together.

Data is written into each address location at the falling edge of the clock and read from the address at the rising edge of the clock. The shift register mode logic automatically controls the positive and negative edge clocking to shift the data in one clock cycle. Figure 2–14 shows the M4K memory block in the shift register mode.

 w × m × n Shift Register

 m-Bit Shift Register

 w

 m-Bit Shift Register

#### Figure 2–14. Shift Register Memory Configuration

#### **Memory Configuration Sizes**

The memory address depths and output widths can be configured as  $4,096 \times 1, 2,048 \times 2, 1,024 \times 4, 512 \times 8$  (or  $512 \times 9$  bits),  $256 \times 16$  (or  $256 \times 18$  bits), and  $128 \times 32$  (or  $128 \times 36$  bits). The  $128 \times 32$ - or 36-bit configuration

#### Single-Port Mode

The M4K memory blocks also support single-port mode, used when simultaneous reads and writes are not required. See Figure 2–21. A single M4K memory block can support up to two single-port mode RAM blocks if each RAM block is less than or equal to 2K bits in size.



#### Note to Figure 2–21:

(1) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

## Global Clock Network and Phase-Locked Loops

Cyclone devices provide a global clock network and up to two PLLs for a complete clock management solution.

#### **Global Clock Network**

There are four dedicated clock pins (CLK[3..0], two pins on the left side and two pins on the right side) that drive the global clock network, as shown in Figure 2–22. PLL outputs, logic array, and dual-purpose clock (DPCLK[7..0]) pins can also drive the global clock network.

#### Figure 2–24. I/O Clock Regions



#### PLLs

Cyclone PLLs provide general-purpose clocking with clock multiplication and phase shifting as well as outputs for differential I/O support. Cyclone devices contain two PLLs, except for the EP1C3 device, which contains one PLL.



Figure 2–32. Cyclone IOE in Bidirectional I/O Configuration

The Cyclone device IOE includes programmable delays to ensure zero hold times, minimize setup times, or increase clock to output times.

A path in which a pin directly drives a register may require a programmable delay to ensure zero hold time, whereas a path in which a pin drives a register through combinatorial logic may not require the delay. Programmable delays decrease input-pin-to-logic-array and IOE input register delays. The Quartus II Compiler can program these delays to automatically minimize setup time while providing a zero hold time. Programmable delays can increase the register-to-pin delays for output registers. Table 2–9 shows the programmable delays for Cyclone devices.

Table 2–9. Cyclone Programmable Delay Chain							
Programmable Delays Quartus II Logic Option							
Input pin to logic array delay	Decrease input delay to internal cells						
Input pin to input register delay	Decrease input delay to input registers						
Output pin delay	Increase delay to output pin						

There are two paths in the IOE for a combinatorial input to reach the logic array. Each of the two paths can have a different delay. This allows you adjust delays from the pin to internal LE registers that reside in two different areas of the device. The designer sets the two combinatorial input delays by selecting different delays for two different paths under the **Decrease input delay to internal cells** logic option in the Quartus II software. When the input signal requires two different delays for the combinatorial input, the input register in the IOE is no longer available.

The IOE registers in Cyclone devices share the same source for clear or preset. The designer can program preset or clear for each individual IOE. The designer can also program the registers to power up high or low after configuration is complete. If programmed to power up low, an asynchronous clear can control the registers. If programmed to power up high, an asynchronous preset can control the registers. This feature prevents the inadvertent activation of another device's active-low input upon power up. If one register in an IOE uses a preset or clear signal then all registers in the IOE must use that same signal if they require preset or clear. Additionally a synchronous reset signal is available to the designer for the IOE registers.

#### **External RAM Interfacing**

Cyclone devices support DDR SDRAM and FCRAM interfaces at up to 133 MHz through dedicated circuitry.

#### DDR SDRAM and FCRAM

Cyclone devices have dedicated circuitry for interfacing with DDR SDRAM. All I/O banks support DDR SDRAM and FCRAM I/O pins. However, the configuration input pins in bank 1 must operate at 2.5 V because the SSTL-2  $V_{CCIO}$  level is 2.5 V. Additionally, the configuration

output pins (nSTATUS and CONF DONE) and all the JTAG pins in I/O bank 3 must operate at 2.5 V because the V<sub>CCIO</sub> level of SSTL-2 is 2.5 V. I/O banks 1, 2, 3, and 4 support DQS signals with DQ bus modes of  $\times 8$ .

For ×8 mode, there are up to eight groups of programmable DQS and DQ pins, I/O banks 1, 2, 3, and 4 each have two groups in the 324-pin and 400-pin FineLine BGA packages. Each group consists of one DQS pin, a set of eight DQ pins, and one DM pin (see Figure 2–33). Each DQS pin drives the set of eight DQ pins within that group.



#### Note to Figure 2-33:

(1) Each DQ group consists of one DQS pin, eight DQ pins, and one DM pin.

Table 2–10 shows the number of DQ pin groups per device.

Table 2–10. DQ Pin Groups (Part 1 of 2)								
Device	Package	Number of × 8 DQ Pin Groups	Total DQ Pin Count					
EP1C3	100-pin TQFP (1)	3	24					
	144-pin TQFP	4	32					
EP1C4	324-pin FineLine BGA	8	64					
	400-pin FineLine BGA	8	64					

Table 2–10. DQ Pin Groups (Part 2 of 2)									
Device	Package	Number of × 8 DQ Pin Groups	Total DQ Pin Count						
EP1C6	144-pin TQFP	4	32						
	240-pin PQFP	4	32						
	256-pin FineLine BGA	4	32						
EP1C12	240-pin PQFP	4	32						
	256-pin FineLine BGA	4	32						
	324-pin FineLine BGA	8	64						
EP1C20	324-pin FineLine BGA	8	64						
	400-pin FineLine BGA	8	64						

Note to Table 2–10:

A programmable delay chain on each DQS pin allows for either a 90° phase shift (for DDR SDRAM), or a 72° phase shift (for FCRAM) which automatically center-aligns input DQS synchronization signals within the data window of their corresponding DQ data signals. The phase-shifted DQS signals drive the global clock network. This global DQS signal clocks DQ signals on internal LE registers.

These DQS delay elements combine with the PLL's clocking and phase shift ability to provide a complete hardware solution for interfacing to high-speed memory.

The clock phase shift allows the PLL to clock the DQ output enable and output paths. The designer should use the following guidelines to meet 133 MHz performance for DDR SDRAM and FCRAM interfaces:

- The DQS signal must be in the middle of the DQ group it clocks
- Resynchronize the incoming data to the logic array clock using successive LE registers or FIFO buffers
- LE registers must be placed in the LAB adjacent to the DQ I/O pin column it is fed by

Figure 2–34 illustrates DDR SDRAM and FCRAM interfacing from the I/O through the dedicated circuitry to the logic array.

<sup>(1)</sup> EP1C3 devices in the 100-pin TQFP package do not have any DQ pin groups in I/O bank 1.

Figure 2–34. DDR SDRAM and FCRAM Interfacing



#### **Programmable Drive Strength**

The output buffer for each Cyclone device I/O pin has a programmable drive strength control for certain I/O standards. The LVTTL and LVCMOS standards have several levels of drive strength that the designer can control. SSTL-3 class I and II, and SSTL-2 class I and II support a minimum setting, the lowest drive strength that guarantees the  $I_{OH}/I_{OL}$ 

#### **Operating Modes**

The Cyclone architecture uses SRAM configuration elements that require configuration data to be loaded each time the circuit powers up. The process of physically loading the SRAM data into the device is called configuration. During initialization, which occurs immediately after configuration, the device resets registers, enables I/O pins, and begins to operate as a logic device. Together, the configuration and initialization processes are called command mode. Normal device operation is called user mode.

SRAM configuration elements allow Cyclone devices to be reconfigured in-circuit by loading new configuration data into the device. With realtime reconfiguration, the device is forced into command mode with a device pin. The configuration process loads different configuration data, reinitializes the device, and resumes user-mode operation. Designers can perform in-field upgrades by distributing new configuration files either within the system or remotely.

A built-in weak pull-up resistor pulls all user I/O pins to  $V_{\rm CCIO}$  before and during device configuration.

The configuration pins support 1.5-V/1.8-V or 2.5-V/3.3-V I/O standards. The voltage level of the configuration output pins is determined by the V<sub>CCIO</sub> of the bank where the pins reside. The bank V<sub>CCIO</sub> selects whether the configuration inputs are 1.5-V, 1.8-V, 2.5-V, or 3.3-V compatible.

#### **Configuration Schemes**

Designers can load the configuration data for a Cyclone device with one of three configuration schemes (see Table 3–5), chosen on the basis of the target application. Designers can use a configuration device, intelligent controller, or the JTAG port to configure a Cyclone device. A low-cost configuration device can automatically configure a Cyclone device at system power-up.

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Tables 4–32 through 4–33 show the external timing parameters on column and row pins for EP1C4 devices.

Table 4–32. EP1C4 Column Pin Global Clock External I/O Timing         Parameters       Note (1)										
Symbol	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee					
Symbol	Min	Max	Min	Max	Min	Max	Unit			
t <sub>INSU</sub>	2.471	_	2.841		3.210		ns			
t <sub>INH</sub>	0.000	—	0.000	—	0.000	—	ns			
t <sub>outco</sub>	2.000	3.937	2.000	4.526	2.000	5.119	ns			
t <sub>INSUPLL</sub>	1.471	—	1.690	—	1.910	—	ns			
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000		ns			
toutcopll	0.500	2.080	0.500	2.392	0.500	2.705	ns			

Table 4–33. EP1C4 Row Pin Global Clock External I/O Timing         Parameters       Note (1)										
Symbol	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee					
Symbol	Min	Max	Min	Max	Min	Max	Unit			
t <sub>INSU</sub>	2.600	_	2.990	_	3.379	—	ns			
t <sub>INH</sub>	0.000	—	0.000	_	0.000	—	ns			
t <sub>outco</sub>	2.000	3.991	2.000	4.388	2.000	5.189	ns			
t <sub>insupll</sub>	1.300	—	1.494	_	1.689	—	ns			
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns			
toutcopll	0.500	2.234	0.500	2.569	0.500	2.905	ns			

Note to Tables 4–32 and 4–33:

(1) Contact Altera Applications for EP1C4 device timing parameters.

Table 4–36. EP1C12 Column Pin Global Clock External I/O Timing         Parameters (Part 2 of 2)								
Symbol	-6 Spee Min	d Grade Max	-7 Speed Grade		-8 Spee Min	8 Speed Grade		
t <sub>INHPLL</sub>	0.000	_	0.000		0.000	_	ns	
t <sub>outcopll</sub>	0.500	1.663	0.500	1.913	0.500	2.164	ns	

Table 4–37. EP1C12 Row Pin Global Clock External I/O Timing Parameters										
	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee					
Symbol	Min	Max	Min	Max	Min	Max	Unit			
t <sub>INSU</sub>	2.620	—	3.012	—	3.404	—	ns			
t <sub>INH</sub>	0.000	_	0.000	_	0.000	—	ns			
t <sub>outco</sub>	2.000	3.671	2.000	4.221	2.000	4.774	ns			
t <sub>INSUPLL</sub>	1.698	_	1.951	_	2.206	—	ns			
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	—	ns			
toutcopll	0.500	1.536	0.500	1.767	0.500	1.998	ns			

Tables 4–38 through 4–39 show the external timing parameters on column and row pins for EP1C20 devices.

Table 4–38. EP1C20 Column Pin Global Clock External I/O Timing Parameters										
Sumbol	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee					
Symbol	Min	Max	Min	Max	Min	Max	Unit			
t <sub>INSU</sub>	2.417	—	2.779	—	3.140	—	ns			
t <sub>INH</sub>	0.000	—	0.000	—	0.000	—	ns			
t <sub>outco</sub>	2.000	3.724	2.000	4.282	2.000	4.843	ns			
t <sub>INSUPLL</sub>	1.417	—	1.629	—	1.840	—	ns			
t <sub>INHPLL</sub>	0.000	—	0.000	—	0.000	—	ns			
toutcopll	0.500	1.667	0.500	1.917	0.500	2.169	ns			

Table 4–39. EP1C20 Row Pin Global Clock External I/O Timing Parameters							
Symbol	-6 Speed Grade		-7 Spee	d Grade	-8 Spee	11	
	Min	Max	Min	Max	Min	Max	UIII
t <sub>INSU</sub>	2.417	_	2.779		3.140		ns
t <sub>INH</sub>	0.000	_	0.000	—	0.000	—	ns
t <sub>outco</sub>	2.000	3.724	2.000	4.282	2.000	4.843	ns
t <sub>XZ</sub>	—	3.645	—	4.191	—	4.740	ns
t <sub>ZX</sub>	—	3.645	—	4.191	—	4.740	ns
t <sub>INSUPLL</sub>	1.417	_	1.629	—	1.840	—	ns
t <sub>INHPLL</sub>	0.000	_	0.000	—	0.000	—	ns
tOUTCOPLL	0.500	1.667	0.500	1.917	0.500	2.169	ns
t <sub>XZPLL</sub>	—	1.588	—	1.826	—	2.066	ns
t <sub>ZXPLL</sub>	_	1.588	_	1.826	_	2.066	ns

### **External I/O Delay Parameters**

External I/O delay timing parameters for I/O standard input and output adders and programmable input and output delays are specified by speed grade independent of device density.

Tables 4–40 through 4–45 show the adder delays associated with column and row I/O pins for all packages. If an I/O standard is selected other than LVTTL 4 mA with a fast slew rate, add the selected delay to the external  $t_{CO}$  and  $t_{SU}$  I/O parameters shown in Tables 4–25 through 4–28.

Table 4–40. Cyclone I/O Standard Column Pin Input Delay Adders (Part 1 of 2)							
I/O Standard	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Unit
LVCMOS	—	0	—	0	—	0	ps
3.3-V LVTTL	—	0	—	0		0	ps
2.5-V LVTTL	—	27	—	31	_	35	ps
1.8-V LVTTL	—	182	—	209		236	ps
1.5-V LVTTL	—	278	—	319		361	ps
SSTL-3 class I	—	-250	—	-288		-325	ps
SSTL-3 class II	_	-250	_	-288		-325	ps
SSTL-2 class I	_	-278	_	-320		-362	ps

Table 4–44. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Column Pins (Part 2 of 2)								
I/O Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	UIII
1.5-V LVTTL	2 mA	—	6,789	—	7,807	—	8,825	ps
	4 mA	—	5,109	—	5,875	—	6,641	ps
	8 mA	—	4,793	—	5,511	—	6,230	ps
SSTL-3 class I		—	1,390	_	1,598	_	1,807	ps
SSTL-3 class II		—	989	_	1,137	_	1,285	ps
SSTL-2 class I		—	1,965	—	2,259	—	2,554	ps
SSTL-2 class II		—	1,692	_	1,945	_	2,199	ps
LVDS		_	802	_	922	_	1,042	ps

Table 4–45. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Row Pins (Part 1 of 2)								
I/O Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		1114
		Min	Max	Min	Max	Min	Max	Unit
LVCMOS	2 mA	—	1,800	—	2,070	—	2,340	ps
	4 mA	_	1,311	—	1,507	_	1,704	ps
	8 mA	—	945	—	1,086	—	1,228	ps
	12 mA	—	807	—	928	—	1,049	ps
3.3-V LVTTL	4 mA	—	1,831	—	2,105	—	2,380	ps
	8 mA	—	1,484	—	1,705	—	1,928	ps
	12 mA	—	973	—	1,118	—	1,264	ps
	16 mA	—	1,012	—	1,163	—	1,315	ps
	24 mA	—	838	—	963	—	1,089	ps
2.5-V LVTTL	2 mA	—	2,747	—	3,158	—	3,570	ps
	8 mA	—	1,757	—	2,019	—	2,283	ps
	12 mA	—	1,763	—	2,026	—	2,291	ps
	16 mA	—	1,623	—	1,865	—	2,109	ps
1.8-V LVTTL	2 mA	—	5,506	—	6,331	—	7,157	ps
	8 mA	—	4,220	—	4,852	—	5,485	ps
	12 mA	—	4,008	—	4,608	—	5,209	ps
1.5-V LVTTL	2 mA	—	6,789	—	7,807	—	8,825	ps
	4 mA	—	5,109	—	5,875	—	6,641	ps
	8 mA	—	4,793	—	5,511	_	6,230	ps
3.3-V PCI			923	_	1,061	_	1,199	ps

Table 4–51. Cyclone Maximum Output Clock Rate for Row Pins					
I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit	
LVTTL	296	285	273	MHz	
2.5 V	381	366	349	MHz	
1.8 V	286	277	267	MHz	
1.5 V	219	208	195	MHz	
LVCMOS	367	356	343	MHz	
SSTL-3 class I	169	166	162	MHz	
SSTL-3 class II	160	151	146	MHz	
SSTL-2 class I	160	151	142	MHz	
SSTL-2 class II	131	123	115	MHz	
3.3-V PCI (1)	66	66	66	MHz	
LVDS	320	303	275	MHz	

*Note to Tables* 4–50 *through* 4–51:

(1) EP1C3 devices do not support the PCI I/O standard. These parameters are only available on row I/O pins.

#### **PLL Timing**

Table 4–52 describes the Cyclone FPGA PLL specifications.

Table 4–52. Cyclone PLL Specifications (Part 1 of 2)					
Symbol	Parameter	Min	Max	Unit	
f <sub>IN</sub>	Input frequency (-6 speed grade)	15.625	464	MHz	
	Input frequency (-7 speed grade)	15.625	428	MHz	
	Input frequency (-8 speed grade)	15.625	387	MHz	
f <sub>IN</sub> DUTY	Input clock duty cycle	40.00	60	%	
t <sub>IN</sub> JITTER	Input clock period jitter	—	± 200	ps	
f <sub>OUT_EXT</sub> (external PLL clock output)	PLL output frequency (-6 speed grade)	15.625	320	MHz	
	PLL output frequency (-7 speed grade)	15.625	320	MHz	
	PLL output frequency (-8 speed grade)	15.625	275	MHz	



# 5. Reference and Ordering Information

#### C51005-1.4

Software	Cyclone <sup>®</sup> devices are supported by the Altera <sup>®</sup> Quartus <sup>®</sup> II design software, which provides a comprehensive environment for system-on-a- programmable-chip (SOPC) design. The Quartus II software includes HDL and schematic design entry, compilation and logic synthesis, full simulation and advanced timing analysis, SignalTap <sup>®</sup> II logic analysis, and device configuration.
· •	For more information about the Quartus II software features, refer to the <i>Quartus II Handbook</i> .
	The Quartus II software supports the Windows 2000/NT/98, Sun Solaris, Linux Red Hat v7.1 and HP-UX operating systems. It also supports seamless integration with industry-leading EDA tools through the NativeLink <sup>®</sup> interface.
Device Pin-Outs	Device pin-outs for Cyclone devices are available on the Altera website (www.altera.com) and in the <i>Cyclone Device Handbook</i> .
Ordering Information	Figure 5–1 describes the ordering codes for Cyclone devices. For more information about a specific package, refer to the <i>Package Information for Cyclone Devices</i> chapter in the <i>Cyclone Device Handbook</i> .